OIPE JC35
JUN 10 2004
PATENT & TRADEMARK OFFICE

Form PTO-1449 (Substitute)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-01014US1	Serial/Patent Number 10/684,661
Information Disclosure Statement BY APPLICANT *(Use several sheets if necessary)*		Applicant/Patent Owner Thomas F. Rust	
		Filing/Issue Date October 14, 2003	Group Art Unit ~~2861~~ 2827

U.S. PATENTS

Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
VN	1	4,340,953	07/20/82	Iwamura et al.	369	126	05/07/80
VN	2	4,575,822	03/11/86	Quate	365	174	02/15/83
VN	3	4,829,507	05/09/89	Kazan et al.	369	126	08/15/88
VN	4	4,831,614	05/16/89	Duerig et al.	369	101	03/13/87
VN	5	4,916,688	04/10/90	Foster et al.	369	126	03/31/88
VN	6	4,945,515	07/31/90	Ooumi et al.	365	174	09/12/88
VN	7	4,962,480	10/09/90	Ooumi et al.	365	151	09/12/88
VN	8	4,987,312	01/22/91	Eigler	250	492.3	11/07/89
VN	9	5,038,322	08/06/91	Van Loenen	365	114	02/03/89
VN	10	5,043,578	08/27/91	Guethner et al.	250	307	04/05/90
VN	11	5,051,977	09/24/91	Goldberg	369	126	08/30/89
VN	12	5,091,880	02/25/92	Isono et al.	365	151	01/29/90
VN	13	5,095,479	03/10/92	Harigaya et al.	369	288	08/12/91
VN	14	5,097,443	03/17/92	Kaneko et al.	365	153	03/28/90
VN	15	5,144,148	09/01/92	Eigler	250	492.3	08/07/90
VN	16	5,187,367	02/16/93	Miyazaki et al.	250	306	08/08/91
VN	17	5,216,631	06/01/93	Sliwa, Jr.	365	174	11/02/90
VN	18	5,251,200	10/05/93	Hatanaka et al.	369	126	09/11/91
VN	19	5,260,567	11/09/93	Kuroda et al.	250	227.19	04/08/92
VN	20	5,262,981	11/16/93	Rabe et al.	365	120	07/01/91
VN	21	5,265,046	11/23/93	Fuchs et al.	365	151	12/30/91
VN	22	5,289,455	02/22/94	Kuroda et al.	369	126	07/23/91

OIPE JUN 10 2004 PATENT & TRADEMARK OFFICE 3600

U.S. PATENTS							
Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
VN	23	5,307,311	04/26/94	Sliwa, Jr.	365	174	02/09/93
VN	24	5,323,375	06/21/94	Ihara et al.	369	126	03/09/92
VN	25	5,335,197	08/02/94	Kaneko et al.	365	153	12/10/91
VN	26	5,389,475	02/14/95	Yanagisawa et al.	430	019	06/18/92
VN	27	5,412,597	5/02/95	Miyazaki et al.	365	174	10/15/93
VN	28	5,446,684	08/29/95	Kaneko et al.	365	046	05/10/94
VN	29	5,453,970	09/26/95	Rust et al.	369	176	07/13/93
VN	30	5,471,064	11/28/95	Koyanagi et al.	250	452.2	09/14/93
VN	31	5,471,458	11/28/95	Oguchi et al.	369	126	09/08/93
VN	32	5,557,596	09/17/96	Gibson et al.	369	101	07/12/95
VN	33	5,606,162	02/25/97	Buser et al.	250	306	07/01/96
VN	34	5,751,685	05/12/98	Yi	369	126	05/10/96
VN	35	5,778,134	07/07/98	Sakai et al.	386	046	09/03/96
VN	36	5,804,710	09/08/98	Mamin et al.	073	105	06/05/97
VN	37	5,808,973	09/15/98	Tanaka	369	14	09/06/96
VN	38	5,822,285	10/13/98	Rugar et al.	369	44.26	03/31/97
VN	39	5,835,477	11/10/98	Binning et al.	369	126	07/10/96
VN	40	5,848,077	12/08/98	Kamae et al.	371	053	12/08/95
VN	41	5,856,967	01/05/99	Mamin et al.	369	126	08/27/97
VN	42	5,929,438	07/27/99	Suzuki et al.	250	306	01/16/97
VN	43	5,953,306	09/14/99	Yi	369	126	04/25/97
VN	44	6,001,519	12/14/99	Yang et al.	430	020	07/02/98
VN	45	6,027,951	02/22/2000	MacDonald et al.	438	020	08/18/98
VN	46	6,038,916	03/21/00	Cleveland et al.	073	105	07/22/97
VN	47	6,196,061	03/06/2001	Adderton et al.	073	105	11/05/98
VN	48	6,275,410 B1	08/14/2001	Morford	365	151	11/09/2000
VN	49	6,339,217	01/15/2002	Kley	250	216	07/28/95

VIET Q. NGUYEN
PRIMARY EXAMINER

OIPE
JUN 10 2004
PATENT & TRADEMARK OFFICE
1600

U.S. PATENTS

Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
VN	50	6,507,552 B2	01/14/2003	Gibson	369	126	12/01/2000
VN	51	6,522,566 B2	02/18/2003	Carter	365	118	12/01/2000
VN	52	6,542,400 B2	04/01/2003	Chen et al.	365	151	03/27/2001

U.S. PATENT PUBLICATIONS

Examiner Initial		Patent Application Publication Number	Publication Date	Applicant
VN	53	US 2002/0110074 A1	08/15/2002	Gibson
VN	54	US 2002/0135917 A1	09/26/2002	Davidson
VN	55	US 2003/0007443 A1	01/09/2003	Nickel
VN	56	US 2003/0081532 A1	05/01/2003	Gibson
VN	57	US 2003/0185139 A1	10/02/2003	Ives
VN	58	US 2003/0189200 A1	10/09/2003	Lee et al.

PENDING U.S. PATENT APPLICATIONS

Examiner Initial		Application Number	Filing Date	First Named Inventor	Petition to Expunge? Yes	No

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Publication Date	Country	Class	Subclass	Translation Yes	Translation No
VN	59	WO 96/11472	04/18/96	PCT				
VN	60	JP3295043	12/26/91	JAPAN			X	
VN	61	JP3295044	12/26/91	JAPAN			X	
VN	62	JP4159636	06/02/92	JAPAN			X	

Attorney Docket No.: LAZE-01014US1
mrobbins/laze/01014us1/firstIDS.wpd

VIET Q. NGUYEN
PRIMARY EXAMINER

104.001:123103
06/07/04-15:46

IDS Date = 6/10/04

OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)		
VN	63	*BO HONG, Exploring the Usage of MEMS-based Storage as Metadata Storage and Disk Cache in Storage Hierarchy,* Storage Systems Research Center, Jack Baskin School of Engineering, University of California at Santa Cruz, 2006 http://www.cse.ucsc.edu/~hongbo/publications/mems-metadata.pdf
VN	64	*SUMIO HOSAKA, HAJIME KOYANAGI AND ATSUSHI KIKUKAWA,* Nanometer Recording on Graphite and Si Substrate Using an Atomic Force Microscope in Air, Japan Journal of Applied Physics, Volume 32 (1993) pp. L464-467, Part 2, No. 3B, March 15, 1993, Central Research Laboratory, Hitachi Limited, Kokubunji, Tokyo 185
VN	65	*ATSUSHI KIKUKAWA, SUMIO HOSAKA, YUKIO HONDA[1] and RYO IMURA,* Phase-Controlled Scanning Force Microscope, Japanese Journal of Applied Physics, Volume 33 (1994) pp. L1286-L1288, Part 2, No. 9A, September 1, 1994, Advanced Research Laboratory, Hitachi Limited, 1-280 Higashi-koigakubo, Kokubunji-shi, Tokyo 185, [1]Central Research Laboratory, Hitachi Limited, 1-280 Higashi-koigakubo, Kokubunji-shi, Tokyo 185
VN	66	*WILLIAM P. KING, DANIEL A. FLETCHER and Y. SUNGTAEK JU,* Nanometer-Scale Thermal Processing for Advanced Manufacturing (YIP '96), Office of Naval Research Annual Grant Report, First Annual Report: May 1, 1996 - April 30, 1997, pp. 1 - 8
VN	67	*T. C. REILEY, T.R. ALBRECHT, D. W. ALBRECHT, K. KUROKI and M. AOYAGI,* A Micro Hard Disk Drive, I.B. M. - Almaden Research Center, I.B.M. Storage System Division, Electrochemical Society Proceeding, Volume 98-20, pp. 10 - 18, 2003
VN	68	*SEIJI HEIKI, YASUO WADA and TOMIHIRO HASHIZUME,* Correlation Between Tip-Apex Shape and Surface Modification by Scanning Tunneling Microscopy, Journal of Applied Physics, Vol. 86, No. 8, pp. 4220 - 4224, 10/1999
VN	69	*MICHAEL BROOKS,* Hole in One, New Scientist, March 27, 1999, pp. 46 - 48
VN	70	*H. JONATHON MAMIN, ROBERT P. RIED, BRUCE D. TERRIS and DANIEL RUGAR,* High-Density Data Storage Based on the Atomic Force Microscope, Proceeding of the IEEE, Volume 87, No. 6, June 1999, pp. 1014 - 1027
VN	71	*STEVEN W. SCHLOSSER, JOHN LINWOOD GRIFFIN, DAVID F. NAGLE, AND GREGORY R. GANER,* Filling the Memory Access Gap: A Case for On-Chip Magnetic Storage, School of Computer Science, Carnegie Mellon University, November 1999
VN	72	*STEVEN W. SCHLOSSER, JOHN LINWOOD GRIFFIN, DAVID F. NAGLE and GREGORY R. GANGER,* Carnegie Mellon University, Designing Computer Systems with MEMS-Based Storage, 9th International Conference on Architectural Support for Programming Languages and Operating Systems, 2000
VN	73	*S. HOSAKA, K. ETOH, A. KIKUKAWA AND H. KOYANAGI,* Megahertz Silicon Atomic Force Microscopy (AFM) Catilever and High-Speed Readout in AFM-Based Recording, Journal of Vacuum Science Technology, Vol 18, No. 1, Janurary/February 2000, pp. 94 - 99
VN	74	*ROBERT P. RIED,* Air-Bearing Sliders and Plane-Plane-Concave Tips for Atomic Force Microscope Cantilevers, Journal of Microelectromechanical Systems, Volume 9, No. 1, March 2000, pp. 52 - 57
VN	75	*L. RICHARD CARLEY, GREGORY R. GANGER and DAVID F. NAGLE, Mems-Based Integrated-Circuit Mass-Storage Systems,* Communications of the ACM, Volume 43, No., 11, November 2000, pp. 73 - 80
VN	76	*P. VETTIGER, M. DESPONT, U. DRECHSLER, U. DURIG, W. HABERLE, M. I. LUTWYCHE, H.E. ROTHUIZEN, R. STUTZ, R. WIDMER AND G. K. BINNIG,* The "Millipede" - More than one thousand tips for future AFM data storage, I.B.M. J. Res. Develop., Volume 44, No. 3, May 2000, pp. 323 - 340

OK VN

Attorney Docket No.: LAZE-01014US1
mrobbins/laze/01014us1/firstIDS.wpd

VIET Q. NGUYEN
PRIMARY EXAMINER

104.001:123103
06/07/04-15:46

IDS Date = 6/10/04

OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)		
VN	77	*R. B. ZMOOD, L. QIN, D. K. SOOD, T. VINAY and D. MEYRICK,* School of Electrical and Computer System Engineering, Royal Melbourne Institute of Technology, Melbourne, Victoria 3000, Australia, Magnetic MEMS Used in Smart Structures Which Exploit Magnetic Materials Properties, Smart Structures and Devices, Proceeding of the SPIE, Volume 4235, 2001, pp. 173 - 187
VN	78	*MICHAEL GROSS,* Small is Great!, New Scientist, July 14, 2001, pp. 1 - 4
VN	79	*G. CHERUBINI, T. ANTONAKOPOULOS, P. BACHTOLD, G. K. BINNIG, M. DESPONT, U. DRECHSLER, A. DHOLAKIA, U. DURIG, E. ELEFTHERIOU, B. GOTSMANN, W. HABERLE, M. A. LANTZ, T. LOELIGER, H. POZIDIS, H. E. ROTHUIZEN, R. STUTZ AND P. VETTIGER,* I.B.M. Research, Zurich Research Laboratory, The Millipede, a Very Dense, Highly Parallel Scanning-Probe Data-Storage System, ESSCIRC 2002, pp. 121 - 125
VN	80	*E. ELEFTHERIOU, G. CHERUBINI, H. POZIDIS, H. E. ROTHUIZEN AND P. VETTIGER,* Millipede - a MEMS-Based Scanning-Probe Data-Storage System, APMRC 2002, pp. 1 - 8
VN	81	*SATOSHI KAWAMURA,* Electronics Device Division, Hitachi Maxell, Limited, Coil on Chip RFID System by Super EF2 Technology, Nippon Oyo Jiki Gakkai Kenkyukai Shiryo, Vol. 123, pp. 21 - 25, 2003
VN	82	Molecular Chip Patent, Poptronics, Vol. 3, No. 5, May 2002, pp. 11 - 12
VN	83	*KENNETH J. KORANE,* A King-Size Future for Nanosize Machines, Machine Design Vol 74, No. 18, September 19, 2002, pp. 88 - 94
VN	84	*PETER VETTIGER AND GERD BINNIG,* The Nanodrive Project: Inventing a Nanotechnology Device for Mass Production and Consumer Use is Trickier than it Sounds, Scientific American, Vol. 288, No. 1, 2002, pp. 47 - 53
VN	85	*MUSTAFA UYSAL, ARIF MERCHANT, GUILLERMO A. ALVAREZ,* Hewlett Packard Laboratories, Using MEMs-Based Storage in Disk Arrays, Proceedings of FAST '03: 2nd USENIX Conference on File and Storage Technologies, USENIX Association, pp. 89 - 101, March 2003
VN	86	*KIYOSHI, T., ET AL.,* "Switching and memory phenomenon in Langmuir-Blodgett film using a scanning tunneling microscope," Canon, Inc., IEIC Technical Report (1994), Vol. 93, No. 524 (OME93 54-59), pp. 7012, Fig. 6, Ref. 15.
VN	87	*KIYOSHI T. ET AL.,* Application and Progress in the Scanning Probe Microscopy, High Density Information Storage Using Langmuir-Blodgett Film and Atomic Force Microscopy," Canon, Inc., Journal of the Surface Science Society of Japan (1997), Vol. 18, No. 4, pp. 213-218, Fig. 7, Ref. 14.
VN	88	*KADO, H. and TOHDA, T.,* "Nanometer-scale recording on chalcogenide films with an atomic force microscope," Appl. Phys./ Lett., Vol. 66, No. 22, 29 May 1995, pp. 2961-2962.
VN	89	*YANO, K., ET AL.,* "Nanometer scale conductance change in a Langmuir-Blodgett film with the atomic force microscope," Appl. Phys. Lett., Vol. 68, Vol. 2, 8 January 1996, pp. 188-190.
VN	90	*YANO, K. and IKEDA, T.,* "Stable bit formation in polyimide Langmuir-Blodgett film using an atomic force microscope," Appl. Phys. Lett., Vol. 80, Vol. 6, 11 February 2002, pp. 1067-1069.
VN	91	*BARRETT, R.C. and QUATE, C.F.,* "Large-scale charge storage by scanning capacitance microscopy," Ultramicroscopy 42-44 (1992) pp. 262-267.
VN	92	*GARDNER, E.,* "AFM Fabricates a Tiny Transistor," Science, Vol. 266, 28 October 1994, p. 543.
VN	93	*HAGAN, H.P.,* et al., "Temporal behaviour of nanofeatures on Au," Ultramicroscopy, 42-44 (1992), pp. 587-593.

OK LW

IDS Date = 6/10/04

OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)		
VN	94	*MAJUMDAR, A., ET AL.*, "Nanometer-scale lithography using the atomic force microscope," Appl. Phys. Lett., Vol. 61, No. 19, 9 November 1992, pp. 2293-2295.
VN	95	*MAMIN, H.J. and RUGER, D.*, "Thermomechanical writing with an atomic force microscope tip," App. Phys. Lett., Vol. 61, No. 8, 24 August 1992, pp. 1003-1005.
VN	96	*MAMIN, H.J., ET AL.*, "High Density data storage using proximal probe techniques," The IBM Journal of Research and Development, Vol. 39, No. 6, November 1995, pp. 681-699.
VN	97	*MANALIS, S., ET AL.*, "Submicron studies of recording media using thin-film magnetic scanning probes," Applied Physics Letters, Vol. 66, No. 19, 8 May 1995, pp. 2585-2587.
VN	98	*TERRIS, B.D., ET AL.*, "Atomic force microscope-base data storage: track servo and wear study," Applied Physics A Vol. 66, pp. S809-S813 (1998), (IBM Almaden Research Center, presented STM 97).
VN	99	*UESUGI, K. and YAO, T.*, "Nanometer-scale fabrication on graphite surfaces by scanning tunneling microscopy," Ultramicroscopy, 42-44 (1992), pp. 1443-1445.
VN	100	PCT Written Opinion mailed December 18, 2000, International Application No. PCT/US99/30326, filed December 20, 1999
VN	101	*T.C. SHEN ET AL;* Ion irradiation effects on graphite with the scanning tunneling microscope; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1376-1379
VN	102	*U. STAUFER ET AL;* Tailoring nanostructures with a scanning tunneling microscope; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1389-1393
VN	103	*H.J. MAMIN;* Gold deposition from a scanning tunneling microscope tip;, et al.; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1398-1402
VN	104	*J.A. DAGATA, ET AL.* Pattern generation on semiconductor surfaces by a scanning tunneling microscope operating in air;; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1384-1388
VN	105	*T.R. ALBRECHT, ET AL.* Nanometer-scale hole formation on graphite using a scanning tunneling microscope;; Appl.Phys.Lett., Vol.55, No.17, 23 October 1989; pp.1727-1729
VN	106	*M.AONO*; Has Japan Begun to Move Toward Atomic Level Material Processing?; Science, Vol. 258; 23 October 1992

Examiner	/Viet Nguyen/ (02/22/2007)	Date Considered	02/22/2007

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

*1 = Copy not submitted because it was submitted in prior application SN _/_____, filed _____, 20___, relied on under 35 USC §120.
*2 = Copy not submitted because it was submitted in prior application SN _/_____, filed _____, 20___, relied on under 35 USC §120.

VIET Q. NGUYEN
PRIMARY EXAMINER

OIPE IAP85 MAY 09 2006 PATENT & TRADEMARK OFFICE

Form PTO-1449 (Substitute)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-01014US1	Application/Patent Number 10/684,661
Information Disclosure Statement BY APPLICANT *(Use several sheets if necessary)*		Applicant/Patent Owner Rust et al.	
		Filing/Issue Date 10/14/03	Group Art Unit 2827

U.S. PATENTS

Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
VN		RE 36,603	03/07/00	Pohl et al.	365	151	08/20/96
VN		5,043,577	08/27/91	Pohl et al.	250	306	10/13/89
VN		5,166,919	11/24/92	Eigler et al.	369	126	07/11/91
VN		5,182,724	01/26/93	Yanagisawa et al.	365	151	09/07/90
VN		5,210,714	05/11/93	Pohl et al.	365	157	03/25/91
VN		5,222,060	06/22/93	Kuroda et al.	369	126	09/05/90
VN		5,264,876	11/23/93	Kawade et al.	346	153.1	01/19/93
VN		5,268,571	12/07/93	Yamamoto et al.	250	306	05/27/92
VN		5,329,514	07/12/94	Eguchi et al.	369	126	07/27/92
VN		5,331,589	07/19/94	Gambino et al.	365	151	10/30/92
VN		5,373,494	12/13/94	Kawagishi et al.	369	126	06/10/92
VN		5,390,161	02/14/95	Kurihara et al.	369	126	05/10/94
VN		5,396,453	03/07/95	Kawada et al.	365	151	07/06/94
VN		5,396,483	03/07/95	Matsuda et al.	369	283	11/18/92
VN		5,398,229	03/14/95	Nakayama et al.	369	126	05/10/94
VN		5,432,771	07/11/95	Shido et al.	369	126	05/03/93
VN		5,481,528	01/02/96	Eguchi et al.	369	126	09/21/93
VN		5,526,334	06/11/96	Yamano et al.	369	53	05/01/95
VN		5,547,774	08/20/96	Gimzewski et al.	428	694	09/01/93
VN		5,623,476	04/22/97	Eguchi et al.	369	126	06/07/95
VN		5,721,721	02/24/98	Yanagisawa et al.	369	126	01/22/96

U.S. PATENTS							
Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
VN		5,793,743	08/11/98	Duerig et al.	369	126	11/03/93
VN		5,812,516	09/22/98	Nose et al.	369	126	06/07/95
VN		5,851,902	12/22/98	Sakai et al.	438	459	02/08/96
VN		5,861,754	01/19/99	Ueno et al.	324	660	07/15/97
VN		5,877,497	03/02/99	Binnig et al.	250	306	05/13/95
VN		5,886,922	03/23/99	Saito et al.	365	164	05/07/97
VN		6,000,021	12/07/99	Saito et al.	711	163	02/19/97
VN		6,000,047	12/07/99	Kamae et al.	714	710	02/10/98
VN		6,017,618	01/25/00	Gupta et al.	428	321.1	10/29/97
VN		6,054,745	04/25/00	Nakos et al.	257	415	1/4/99
VN		6,088,320	07/11/00	Bayer et al.	369	101	02/19/97
VN		6,236,589	05/22/01	Gupta et al.	365	151	5/26/99
VN		6,359,755	03/19/02	Dietzel et al.	360	244.3	7/15/99
VN		6,411,589	06/25/02	Hoen et al.	369	126	07/29/98
VN		6,501,210	12/31/02	Ueno et al.	310	331	08/29/97
VN		6,611,033	08/26/03	Hsu et al.	257	414	4/12/01
VN		6,611,140	08/26/03	Bloechl et al.	324	207	3/8/02
VN		6,628,452	09/30/03	Haeberle	359	298	09/05/01
VN		6,665,258	12/16/03	Dietzel et al.	369	126	07/03/00
VN		6,680,808	01/20/04	Allenspach et al.	360	59	3/1/01
VN		6,819,587	11/16/04	Sharma et al.	365	173	06/12/03
VN		6,862,206	03/01/05	Carter et al.	365	151	12/19/03
VN		6,930,368	08/16/05	Hartwell et al.	257	418	07/31/03

U.S. PATENT PUBLICATIONS				
Examiner Initial		Patent Application Publication Number	Publication Date	Applicant
VN		2002/0110074	08/15/02	Gibson
VN		2002/0173153	11/21/02	Lee et al.
VN		2003/020725	11/06/03	Trivedi
VN		2003/0128494	07/10/03	Birecki et al.
VN		2003/0081532	05/01/03	Gibson
VN		2003/0081527	05/01/03	Gibson et al.
VN		2003/0189200	10/09/03	Lee et al.
VN		2003/0032290	02/13/03	Lee et al.
VN		2003/0007443	01/09/03	Nickel
VN		2003/0218960	11/27/03	Albrecht et al.
VN		2004/0090823	05/13/04	Brocklin et al.
VN		2004/0107770	06/10/04	Despont et al.
VN		2004/0252553	12/16/04	Sharma
VN		2004/0097002	05/20/04	Pogge et al.
VN		2004/0257887	12/23/04	Binnig et al.
VN		2004/0233817	11/25/04	Antonakopoulos et al.
VN		2004/0218507	11/04/04	Binnig et al.
VN		2004/0136277	07/15/04	Binnig et al.
VN		2004/0114490	06/17/04	Antonakopoulos et al.
VN		2004/0105323	06/03/04	Giovanni et al.
VN		2004/0071021	04/15/04	Binnig et al.
VN		2004/0047275	03/11/04	Cherubini et al.
VN		2004/0252590	12/16/04	Sharma
VN		2004/0095868	05/20/04	Birecki et al.
VN		2004/0077123	04/22/04	Lee et al.
VN		2004/0113641	06/17/04	Birecki et al.

U.S. PATENT PUBLICATIONS				
Examiner Initial		Patent Application Publication Number	Publication Date	Applicant
VN		2005/0066107	03/24/05	Bachtold et al.
VN		2005/0050258	03/03/05	Frommer et al.
VN		2005/0047307	03/03/05	Frommer et al.
VN		2005/0122786	06/09/05	Antonakopoulos et al.
VN		2005/0259503	11/24/05	Hilton
VN		2005/0157575	07/21/05	Binnig et al.
VN		2005/0286321	12/29/05	Adelmann
VN		2005/0169063	08/04/05	Cherubini et al.
VN		2005/0233596	10/20/05	Chen et al.
VN		2005/0281075	12/22/05	Chen et al.
VN		2005/0185567	08/25/05	Adelmann
VN		2005/0201257	09/15/05	Champion et al.
VN		2005/0201256	09/15/05	Champion et al.
VN		2005/0201255	09/15/05	Champion et al.
VN		2005/0037560	02/17/05	Duerig et al.
VN		2005/0157562	07/21/05	Smith et al.
VN		2005/0156271	07/21/05	Lam et al.
VN		2005/0147017	07/07/05	Gibson
VN		2005/0139883	06/30/05	Sharma
VN		2005/0135224	06/23/05	Mejia et al.
VN		2005/0135203	06/23/05	Mejia et al.
VN		2005/0135200	06/23/05	Mejia et al.
VN		2005/0135199	06/23/05	Mejia et al.
VN		2005/0128927	06/16/05	Milligan et al.
VN		2005/0088873	04/28/05	Tran et al.
VN		2005/0082598	04/21/05	Liao et al.

U.S. PATENT PUBLICATIONS				
Examiner Initial		Patent Application Publication Number	Publication Date	Applicant
VN		2005/0055170	03/10/05	Gibson et al.
VN		2005/0038950	02/17/05	Adelmann
VN		2005/0036428	02/17/05	Adelmann
VN		2005/0029920	02/10/05	Birecki et al.
VN		2005/0025034	02/03/05	Gibson
VN		2005/0013230	01/20/05	Adelmann
VN		2005/0226117	10/13/05	Champion et al.
VN		2005/0018588	01/27/05	Duerig et al
VN		2005/0281174	12/22/05	Gotsmann et al.
VN		2005/0207234	09/22/05	Baechtold Peter et al.
VN		2005/0237906	10/27/05	Gibson
VN		2005/0259366	11/24/05	Champion et al.
VN		2005/0247873	11/10/05	Hilton
VN		2005/0201258	09/15/05	Champion et al.
VN		2006/0023612	02/02/06	Hilton et al.
VN		2006/0023613	02/02/06	Mejia et al.
VN		2006/0028964	02/09/06	Mejia et al.
VN		2006/0028965	02/09/06	Fasen et al
VN		2006/0039250	02/23/06	Cherubini et al.
VN		2006/0006471	01/29/06	Rossel et al.
VN		2006/0003493	01/05/06	Milligan et al.

PENDING U.S. PATENT APPLICATIONS						
Examiner Initial		Application Number	Filing Date	First Named Inventor	Petition to Expunge? Yes	No

PENDING U.S. PATENT APPLICATIONS						
Examiner Initial		Application Number	Filing Date	First Named Inventor	Petition to Expunge? Yes	No

FOREIGN PATENT DOCUMENTS								
Examiner Initial		Document Number	Publication Date	Country	Class	Subclass	Trans-lation Yes	No

OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)		

Examiner	/Viet Nguyen/ (02/22/2007)	Date Considered	02/22/2007

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

*1 = Copy not submitted because it was submitted in prior application SN _/_____, filed _____, 20___, relied on under 35 USC §120.

**2 = Copy not submitted because it was submitted in prior application SN _/_____, filed _____, 20___, relied on under 35 USC §120.

VIET Q. NGUYEN
PRIMARY EXAMINER